

# Tony Schenk

## List of Publications by Year in descending order

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59  
papers

6,077  
citations

159585

30  
h-index

223800

46  
g-index

59  
all docs

59  
docs citations

59  
times ranked

2445  
citing authors

#	ARTICLE	IF	CITATIONS
1	Influence of substrate stress on in-plane and out-of-plane ferroelectric properties of PZT films. Journal of Applied Physics, 2022, 131, 014101.	2.5	5
2	Highly conductive low-temperature combustion-derived transparent indium tin oxide thin film. Materials Advances, 2021, 2, 700-705.	5.4	9
3	Enhancement of ferroelectricity and orientation in solution-derived hafnia thin films through heterogeneous grain nucleation. Applied Physics Letters, 2021, 118, .	3.3	11
4	Emerging Fluorite- and Wurtzite-Type Ferroelectrics: From (Hf,Zr)O <sub>2</sub> to AlN and Related Materials. Physica Status Solidi - Rapid Research Letters, 2021, 15, 2100201.	2.4	2
5	A New Generation of Memory Devices Enabled by Ferroelectric Hafnia and Zirconia. , 2021, , .		11
6	Influence of tensile vs. compressive stress on fatigue of lead zirconate titanate thin films. Journal of the European Ceramic Society, 2021, 41, 6991-6999.	5.7	10
7	Toward Thick Piezoelectric HfO <sub>2</sub> -Based Films. Physica Status Solidi - Rapid Research Letters, 2020, 14, 1900626.	2.4	41
8	Memory technology—a primer for material scientists. Reports on Progress in Physics, 2020, 83, 086501.	20.1	64
9	Fully Transparent Friction-Modulation Haptic Device Based on Piezoelectric Thin Film. Advanced Functional Materials, 2020, 30, 2003539.	14.9	25
10	On the importance of pyrolysis for inkjet-printed oxide piezoelectric thin films. Journal of Materials Chemistry C, 2020, 8, 3740-3747.	5.5	7
11	Effect of Dopant Ordering on the Stability of Ferroelectric Hafnia. Physica Status Solidi - Rapid Research Letters, 2020, 14, 2000047.	2.4	15
12	AFE-like Hysteresis Loops from Doped HfO <sub>2</sub> : Field Induced Phase Changes and Depolarization Fields. , 2020, , .		2
13	On the Origin of the Large Remanent Polarization in La:HfO <sub>2</sub> . Advanced Electronic Materials, 2019, 5, 1900303.	5.1	85
14	Fluid Imprint and Inertial Switching in Ferroelectric La:HfO <sub>2</sub> Capacitors. ACS Applied Materials & Interfaces, 2019, 11, 35115-35121.	8.0	58
15	Local structural investigation of hafnia-zirconia polymorphs in powders and thin films by X-ray absorption spectroscopy. Acta Materialia, 2019, 180, 158-169.	7.9	19
16	Dopants in Atomic Layer Deposited HfO <sub>2</sub> Thin Films. , 2019, , 49-74.		13
17	Impact of Electrodes on the Ferroelectric Properties. , 2019, , 341-364.		3
18	Effect of Surface/Interface Energy and Stress on the Ferroelectric Properties. , 2019, , 145-172.		5

#	ARTICLE	IF	CITATIONS
19	Piezoresponse Force Microscopy (PFM). , 2019, , 291-316.		4
20	Field Cycling Behavior of Ferroelectric HfO <sub>2</sub> -Based Capacitors. , 2019, , 381-398.		4
21	Pyroelectricity of silicon-doped hafnium oxide thin films. Applied Physics Letters, 2018, 112, 142901.	3.3	42
22	Origin of Temperature-Dependent Ferroelectricity in Si-Doped HfO <sub>2</sub> . Advanced Electronic Materials, 2018, 4, 1700489.	5.1	67
23	Lanthanum-Doped Hafnium Oxide: A Robust Ferroelectric Material. Inorganic Chemistry, 2018, 57, 2752-2765.	4.0	241
24	Atomic Structure of Domain and Interphase Boundaries in Ferroelectric HfO <sub>2</sub> . Advanced Materials Interfaces, 2018, 5, 1701258.	3.7	114
25	Physical Approach to Ferroelectric Impedance Spectroscopy: The Rayleigh Element. Physical Review Applied, 2018, 10, .	3.8	14
26	Effect of Annealing Ferroelectric HfO <sub>2</sub> Thin Films: In Situ, High Temperature X-Ray Diffraction. Advanced Electronic Materials, 2018, 4, 1800091.	5.1	81
27	Nanosopic studies of domain structure dynamics in ferroelectric La:HfO <sub>2</sub> capacitors. Applied Physics Letters, 2018, 112, .	3.3	85
28	Genuinely Ferroelectric Sub-1-Volt-Switchable Nanodomains in Hf <sub>x</sub> Zr <sub>(1-x)</sub> O <sub>2</sub> Ultrathin Capacitors. ACS Applied Materials & Interfaces, 2018, 10, 30514-30521.	8.0	36
29	Domain Pinning: Comparison of Hafnia and PZT Based Ferroelectrics. Advanced Electronic Materials, 2017, 3, 1600505.	5.1	99
30	A comprehensive study on the structural evolution of HfO <sub>2</sub> thin films doped with various dopants. Journal of Materials Chemistry C, 2017, 5, 4677-4690.	5.5	250
31	Ferroelectric and piezoelectric properties of Hf <sub>1-x</sub> Zr <sub>x</sub> O <sub>2</sub> and pure ZrO <sub>2</sub> films. Applied Physics Letters, 2017, 110, .	3.3	141
32	Effect of acceptor doping on phase transitions of HfO <sub>2</sub> thin films for energy-related applications. Nano Energy, 2017, 36, 381-389.	16.0	64
33	Surface and grain boundary energy as the key enabler of ferroelectricity in nanoscale hafnia-zirconia: a comparison of model and experiment. Nanoscale, 2017, 9, 9973-9986.	5.6	249
34	Silicon-doped hafnium oxide anti-ferroelectric thin films for energy storage. Journal of Applied Physics, 2017, 122, .	2.5	93
35	Si Doped Hafnium Oxide- A "Fragile" Ferroelectric System. Advanced Electronic Materials, 2017, 3, 1700131.	5.1	136
36	Insights into antiferroelectrics from first-order reversal curves. Applied Physics Letters, 2017, 111, .	3.3	25

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37	Physical Mechanisms behind the Field-Cycling Behavior of HfO <sub>2</sub> -Based Ferroelectric Capacitors. <i>Advanced Functional Materials</i> , 2016, 26, 4601-4612.	14.9	586
38	Impact of charge trapping on the ferroelectric switching behavior of doped HfO <sub>2</sub> . <i>Physica Status Solidi (A) Applications and Materials Science</i> , 2016, 213, 270-273.	1.8	28
39	Structural Changes Underlying Field-Cycling Phenomena in Ferroelectric HfO <sub>2</sub> Thin Films. <i>Advanced Electronic Materials</i> , 2016, 2, 1600173.	5.1	301
40	Impact of field cycling on HfO <sub>2</sub> based non-volatile memory devices. , 2016, , .		6
41	Comparison of hafnia and PZT based ferroelectrics for future non-volatile FRAM applications. , 2016, , .		21
42	Evidence of single domain switching in hafnium oxide based FeFETs: Enabler for multi-level FeFET memory cells. , 2015, , .		93
43	The Rayleigh law in silicon doped hafnium oxide ferroelectric thin films. <i>Physica Status Solidi - Rapid Research Letters</i> , 2015, 9, 589-593.	2.4	10
44	Correspondence - Dynamic leakage current compensation revisited. <i>IEEE Transactions on Ultrasonics, Ferroelectrics, and Frequency Control</i> , 2015, 62, 596-599.	3.0	10
45	Complex Internal Bias Fields in Ferroelectric Hafnium Oxide. <i>ACS Applied Materials &amp; Interfaces</i> , 2015, 7, 20224-20233.	8.0	200
46	On the structural origins of ferroelectricity in HfO <sub>2</sub> thin films. <i>Applied Physics Letters</i> , 2015, 106, .	3.3	447
47	Low Temperature Compatible Hafnium Oxide Based Ferroelectrics. <i>Ferroelectrics</i> , 2015, 480, 16-23.	0.6	24
48	Stabilizing the ferroelectric phase in doped hafnium oxide. <i>Journal of Applied Physics</i> , 2015, 118, .	2.5	424
49	Electric field and temperature scaling of polarization reversal in silicon doped hafnium oxide ferroelectric thin films. <i>Acta Materialia</i> , 2015, 99, 240-246.	7.9	89
50	Impact of different dopants on the switching properties of ferroelectric hafniumoxide. <i>Japanese Journal of Applied Physics</i> , 2014, 53, 08LE02.	1.5	318
51	About the deformation of ferroelectric hystereses. <i>Applied Physics Reviews</i> , 2014, 1, 041103.	11.3	159
52	Film properties of low temperature HfO <sub>2</sub> grown with H <sub>2</sub> O, O <sub>3</sub> , or remote O <sub>2</sub> -plasma. <i>Journal of Vacuum Science and Technology A: Vacuum, Surfaces and Films</i> , 2014, 32, .	2.1	19
53	Electric Field Cycling Behavior of Ferroelectric Hafnium Oxide. <i>ACS Applied Materials &amp; Interfaces</i> , 2014, 6, 19744-19751.	8.0	154
54	Ferroelectricity in Si-Doped HfO <sub>2</sub> Revealed: A Binary Lead-Free Ferroelectric. <i>Advanced Materials</i> , 2014, 26, 8198-8202.	21.0	147

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55	Identification of the ferroelectric switching process and dopant-dependent switching properties in orthorhombic HfO <sub>2</sub> : A first principles insight. Applied Physics Letters, 2014, 104, .	3.3	183
56	Ferroelectric hafnium oxide: A CMOS-compatible and highly scalable approach to future ferroelectric memories. , 2013, , .		271
57	Strontium doped hafnium oxide thin films: Wide process window for ferroelectric memories. , 2013, , .		84
58	Wake-up effects in Si-doped hafnium oxide ferroelectric thin films. Applied Physics Letters, 2013, 103, .	3.3	309
59	Doped Hafnium Oxide “ An Enabler for Ferroelectric Field Effect Transistors. Advances in Science and Technology, 0, , .	0.2	64